

# **Convenzione Quadro INFN PAT Progetto MEMS**

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**Giornata INFN Spazio**

**LNF**

**16 febbraio 2005**

# **Programmi di ricerca nell' ambito della Convenzione PAT- INFN**

L' INFN e la Provincia Autonoma di Trento (PAT), tramite il Comitato paritetico presieduto da P.Dal Piaz, hanno preparato 2003 il progetto esecutivo di due programmi di ricerca, nell' ambito della convenzione sottoscritta il 31 luglio 2001.

I due programmi sono:

- 1- “SAE” finalizzato allo sviluppo di sistemi di calcolo avanzati in ambito GRID;**
- 2 “MEMS” finalizzato allo sviluppo di microsistemi innovativi per la realizzazione per esperimenti di alta energia, attivita’ spaziali, applicazioni medicali ed altro.**

Il Direttivo dell' INFN ha approvato nella riunione del settembre 2003 una lettera di intenti per l'attuazione di questi programmi nella misura fino al 40% del costo complessivo.

La Giunta Provinciale di Trento, nella riunione del 30 dicembre 2003, ha approvato un impegno di spesa di **3.690.000,00 Euro**, per la realizzazione di tali programmi comprendendo il finanziamento di sei borse di studio triennali.

# Il programma MEMS

Il **programma MEMS** prevede inizialmente i seguenti quattro sottoprogetti di interesse congiunto INFN/ITC-irst:

1. Sviluppo di rivelatori di radiazione in silicio ad alta resistività con elettrodi tridimensionali .
2. Sviluppo di matrici di microfotomoltiplicatori al silicio per la rivelazione di luce .
3. Sviluppo di matrici di microbolometri.
4. Sviluppo di una Time Projection Chamber (TPC) basata su silicio a bassa temperatura.

# Convenzione Quadro PAT-INFN

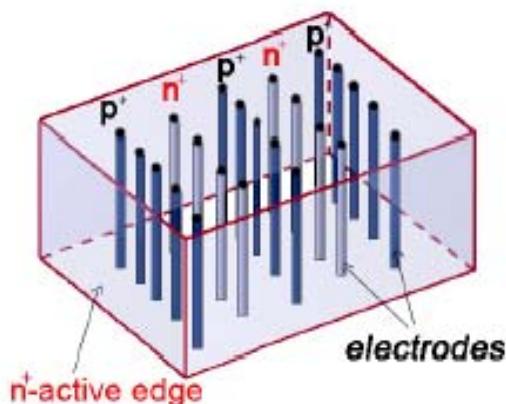
**Programma MEMS**

**P1. Rivelatori al silicio 3D**

# 3D SILICON DETECTORS

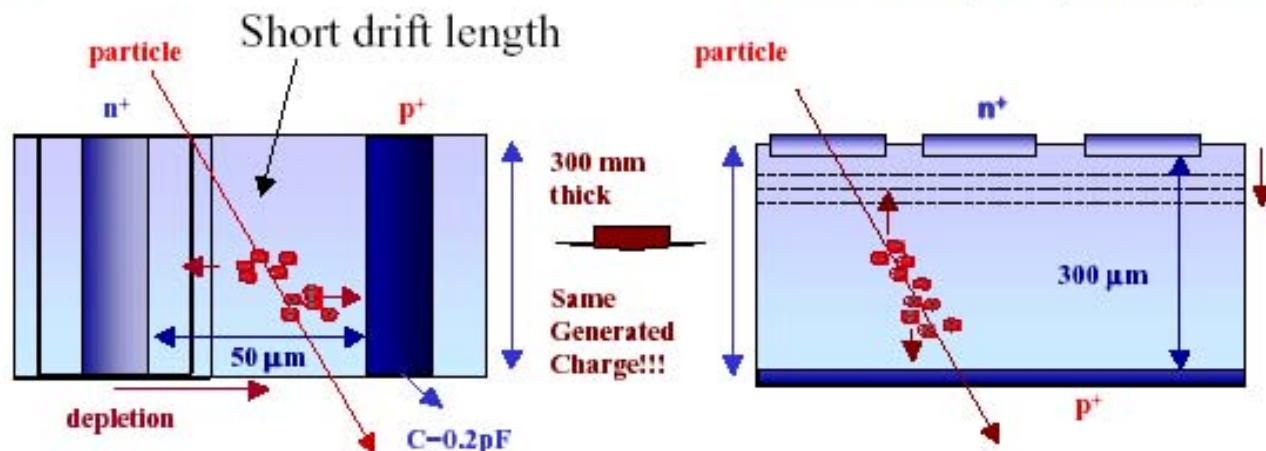
S. Parker, C. Kenney  
Stanford 1995

combination of VLSI and micromachining technologies (MEMS MicroElectroMechanicalSystems)



- ❖ FZ silicon
- ❖ n- and p-type substrates
- ❖ High resistivity  $k\Omega\text{-cm}$
- ❖ <100> orientation

- ❖ IEEE Trans Nucl Scie 46 4 (1999) 1224
- ❖ IEEE Trans Nucl Scie 48 2 (2001) 189
- ❖ IEEE Trans Nucl Scie 48 6 (2001) 2405
- ❖ IEEE Trans Nucl Scie 48 5 (2001) 1629
- ❖ CERN Courier, Vol 43, Number 1, Jan 2003



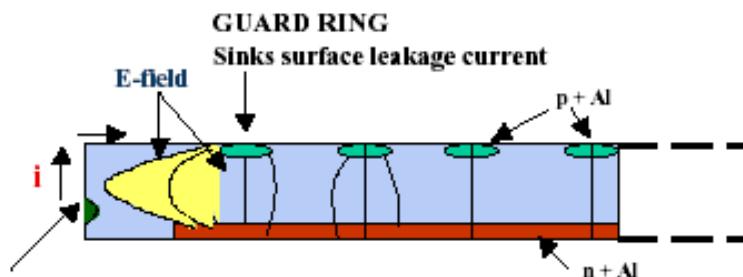
# 3D ACTIVE EDGES

**PLANAR TECHNOLOGY**  
E-field lines need to be contained  
TO PREVENT HIGH SURFACE  
LEAKAGE CURRENT

EDGE SENSITIVITY  $\sim 500 \mu\text{m}$

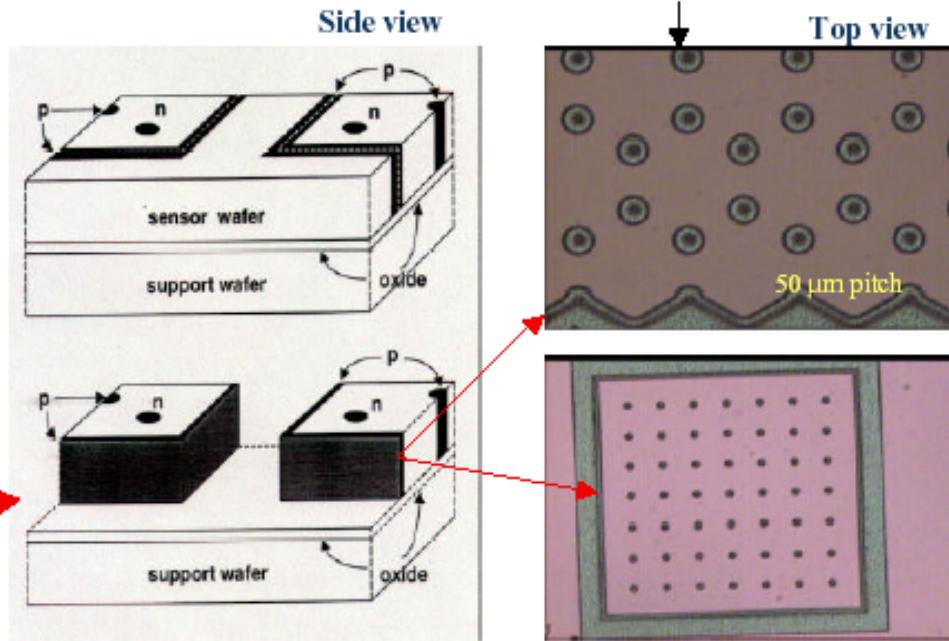
**3D TECHNOLOGY**  
E-field line ends into the  
edge (p) electrode  
  
EDGE SENSITIVITY  $<10 \mu\text{m}$

AFTER PROCESSING THE  
MATERIAL SURROUNDING  
THE DETECTORS IS ETCHED  
AWAY: NO SAWING NEEDED!!!



Microcracks , chips  
Free charge from dangling bonds

Pictures of processed structures  
Brunel, Hawaii, Stanford Jan. 2003



# Interesse duale dei Silicon 3D

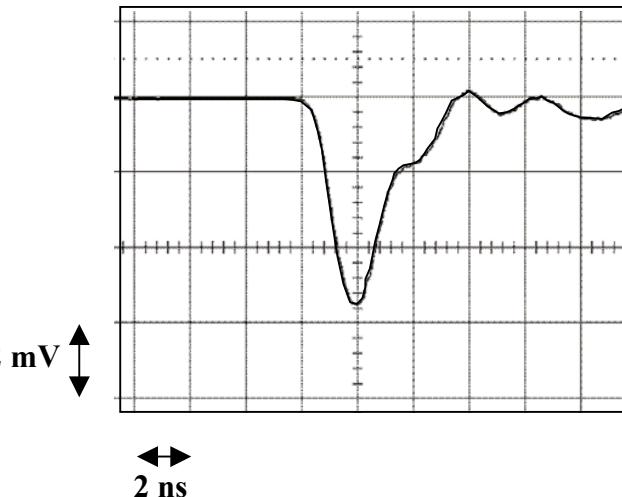
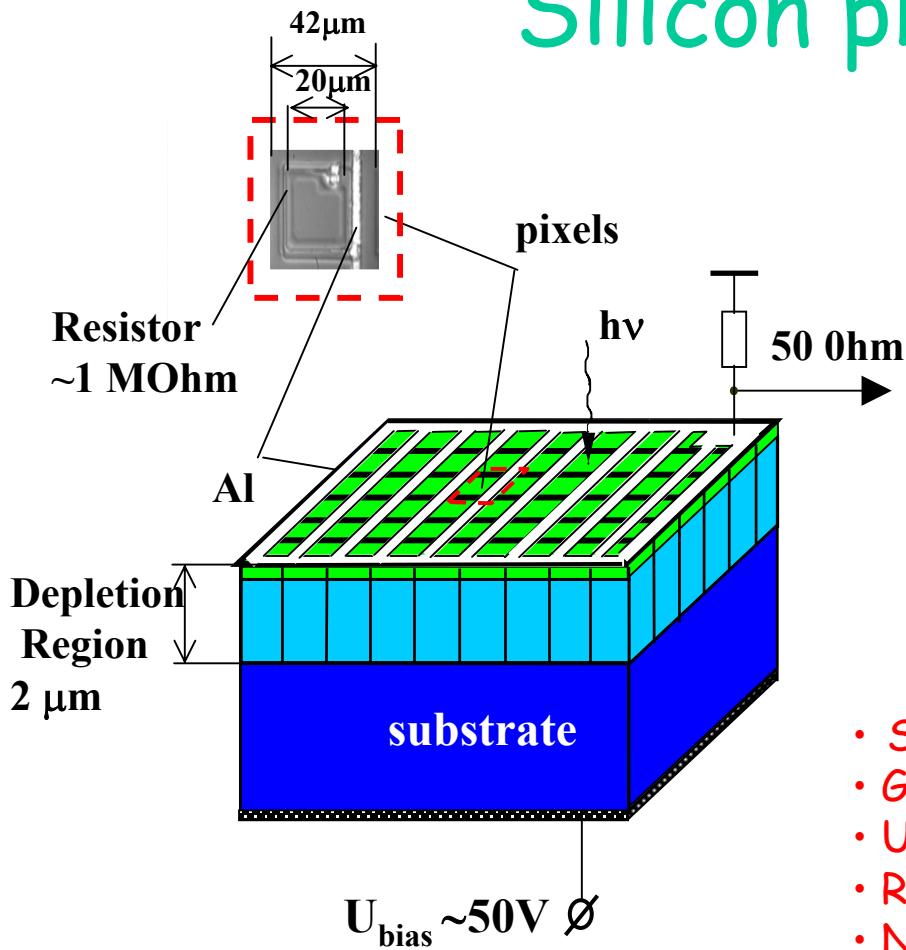
- *Imaging ad alta velocita' in presenza di alte dosi e alti rates*
- *Resistenza alla radiazione*

# Convenzione Quadro PAT-INFN

**Programma MEMS**

**P2. Sviluppo di matrici di  
SiPM**

# Silicon photomultiplier (SiPM)

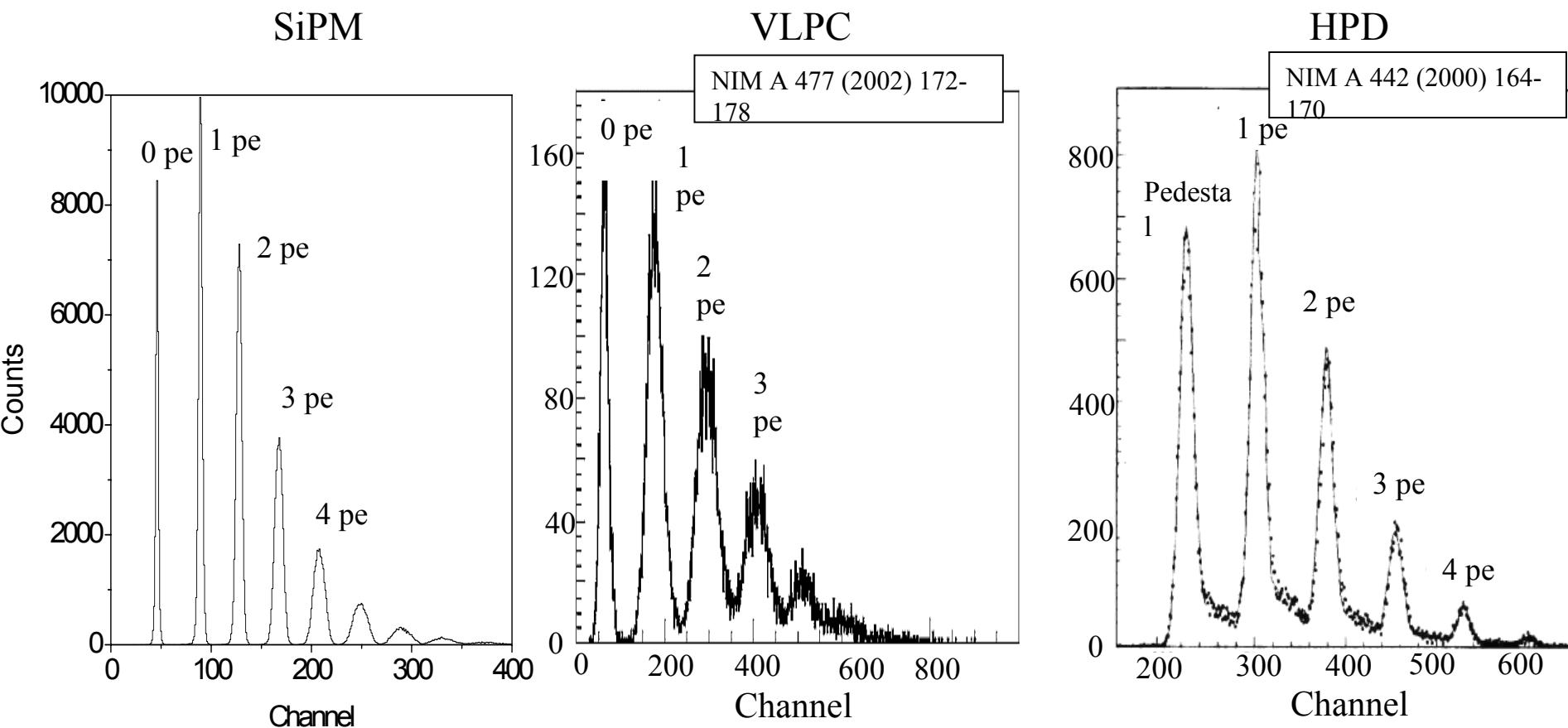


## SiPM main features:

- Sensitive size  $1 \times 1 \text{ mm}^2$  on chip  $1.5 \times 1.5 \text{ mm}^2$
- Gain  $2 \cdot 10^6$
- $U_{\text{bias}} \sim 50 \text{ V}$
- Recovery time  $< 100 \text{ ns/pixel}$
- Number of pixels:  $\sim 1000/\text{mm}^2$
- Nuclear counter effect: negligible (due to Geiger mode)
- Insensitive to magnetic field
- Dynamic range  $\sim 10^3/\text{mm}^2$

for details: NIMA  
504(2003)48

# Single photoelectron (single pixel) spectra



**SiPM:**

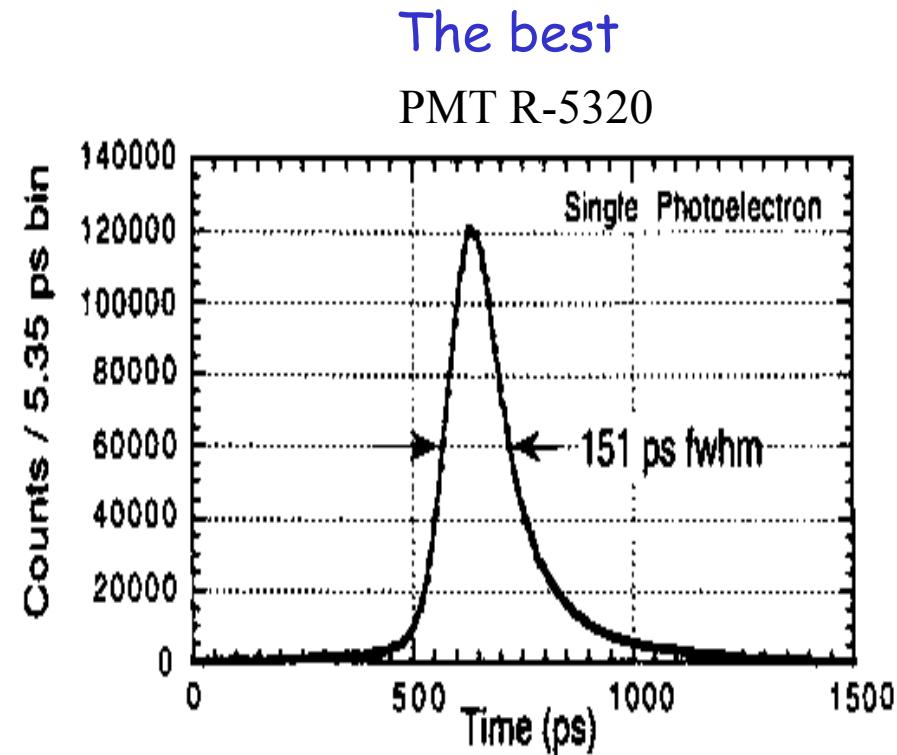
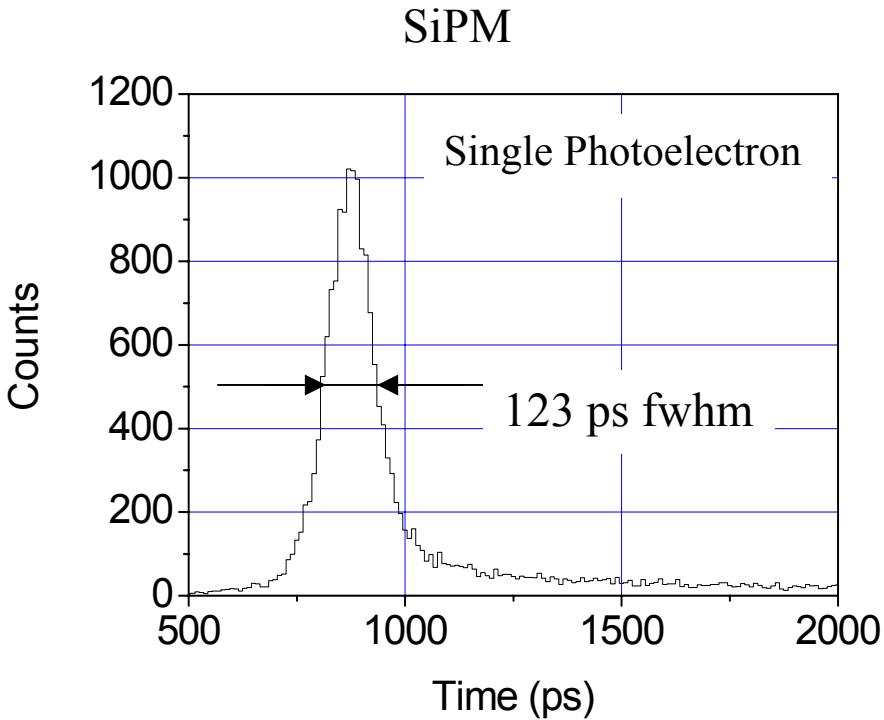
- excellent single photoelectron resolution
- low ENF expected

# *SiPMT characteristics compared*

Table 1:

|                                 | PMT                | APD                            | HPD                                    | SiPM                    |
|---------------------------------|--------------------|--------------------------------|--|-------------------------|
| Photon detection efficiency:    |                    |                                |  |                         |
| blue                            | 20%                | 50%                            | 20%                                    | 12%                     |
| green - yellow                  | a few %            | 60-70%                         | a few %                                | 15%                     |
| red                             | <1%                | 80%                            | <1%                                    | 15%                     |
| Gain                            | $10^6\text{-}10^7$ | 100-200                        | $10^3$                                 | $10^6$                  |
| High voltage                    | 1-2 kV             | 100-500 V                      | 20 kV                                  | 25 V                    |
| Operation in the magnetic field | problematic        | OK                             | OK                                     | OK                      |
| Threshold sensitivity           | 1 ph.e.            | ~10 ph.e.                      | 1 ph.e.                                | 1 ph.e.                 |
| S/N $\gg$ 1                     |                    |                                |  |                         |
| Timing /10 ph.e.                | ~100 ps            | a few ns                       | ~100 ps                                | 30 ps                   |
| Dynamic range                   | $\sim 10^6$        | large                          | large                                  | $\sim 10^3/\text{mm}^2$ |
| Complexity                      | high (vacuum, HV)  | medium (low noise electronics) | very high (hybrid technology, very HV) | relatively low          |

# Timing by SiPM



FWHM: Laser (40 ps) + electronics (40 ps) => SiPM  
(100 ps)

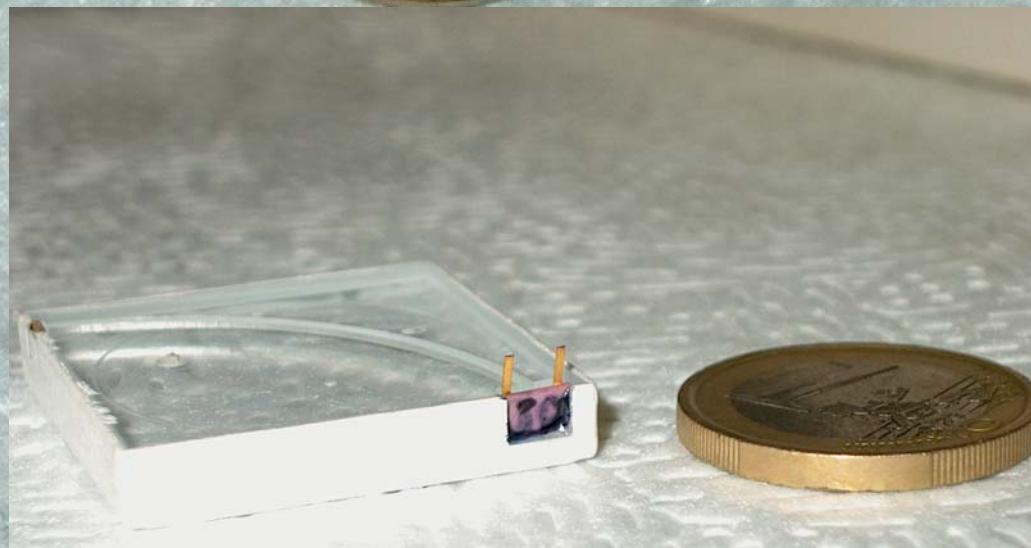
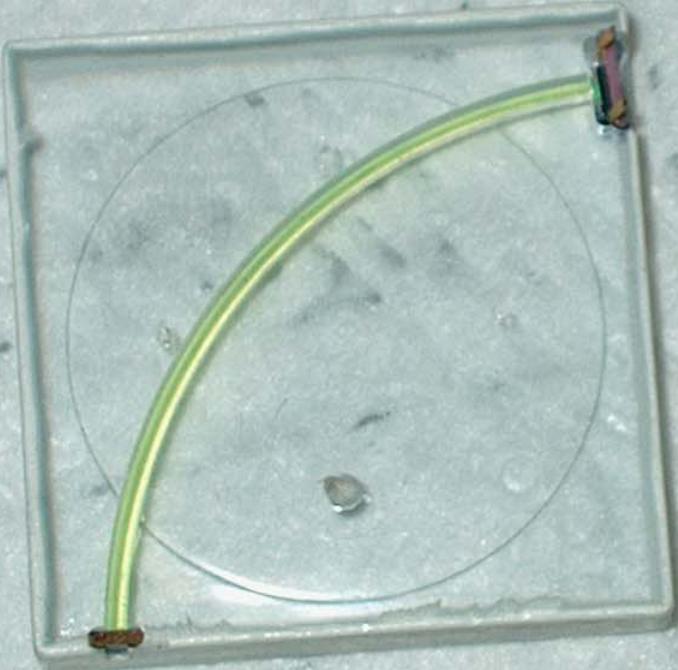
**50 ps sigma for single ph.e. by leading edge discriminator**

- SiPM timing performance competes with MCP PM

# SiPM: arguments in favour

- ✓ Low noise, high gain
- ✓ Good single electron resolution
  - ✓ Very good timing
  - ✓ Small recovery time
- ✓ Low charge particle/photon sensitivity
  - ✓ Insensitivity to B
  - ✓ Low bias voltage
- ✓ Low power consumption
  - ✓ Compactness
- ✓ Room temperature operation
- ✓ Good temperature and voltage stability
  - ✓ Simplest electronics
- ✓ Relatively low cost (low resistivity Si, simple technology)

# MEMS Silicon Photomultipliers for the LAZIO-SiRad scintillating tiles



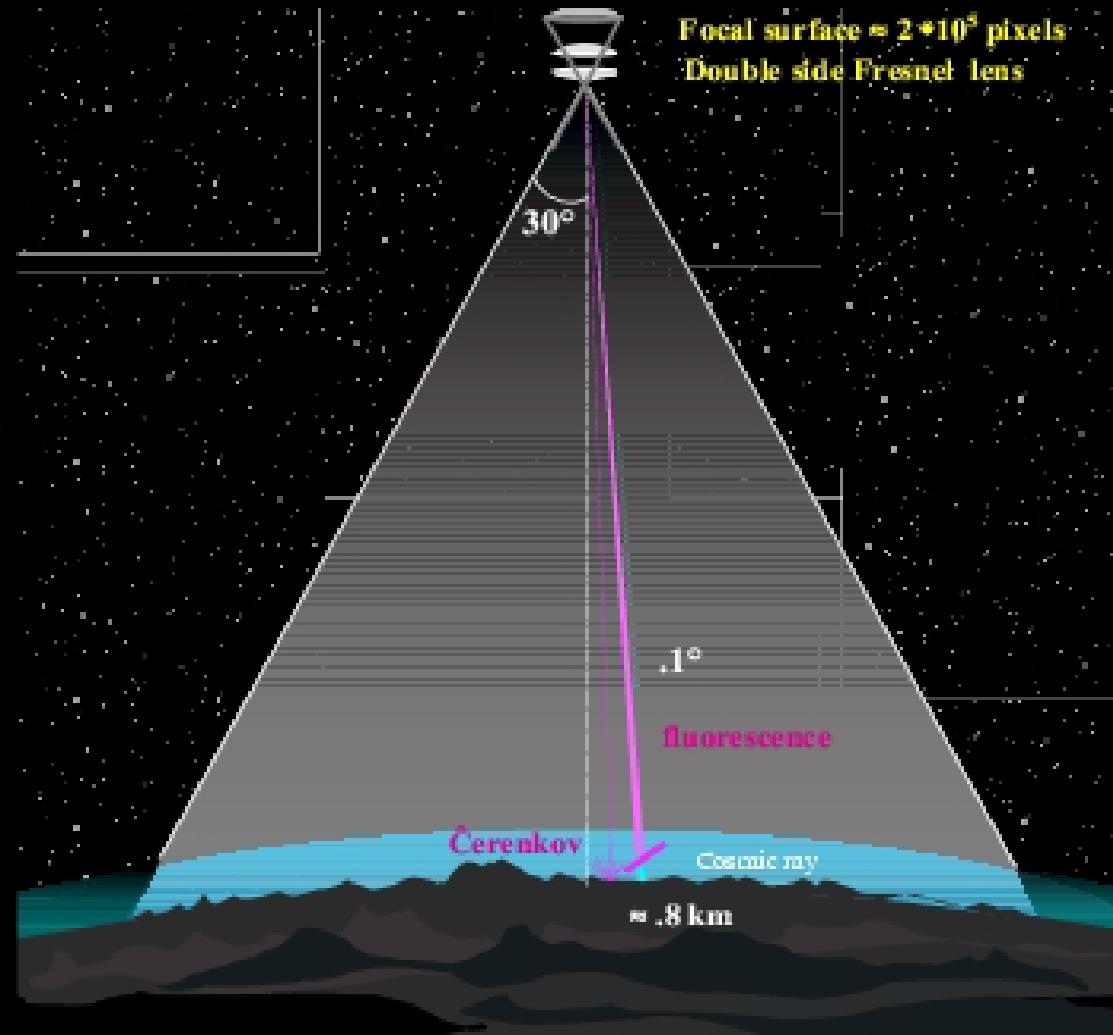
# SiPM for a single photon counting: Possible application for EUSO experiment

EUSO-  
Extreme UniverseSpace Observatory

## EUSO on the ISS

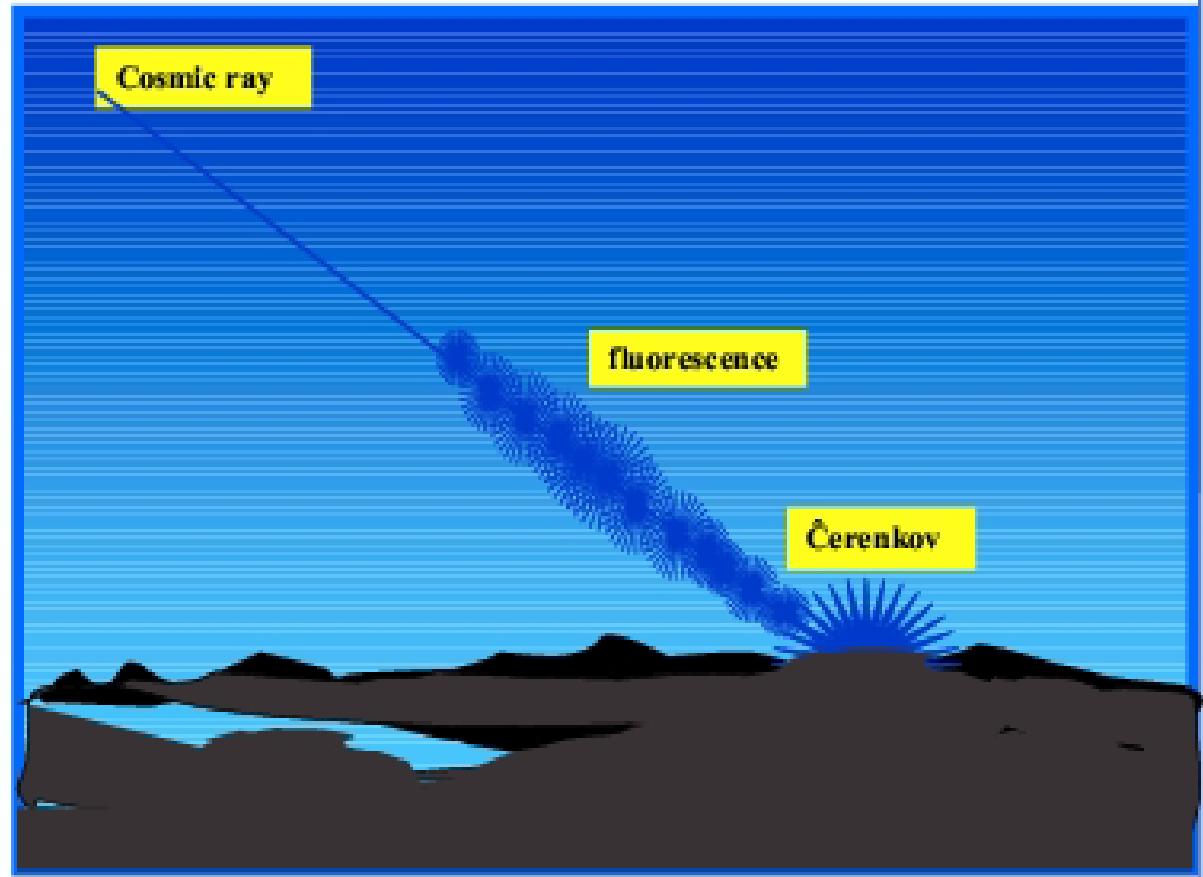
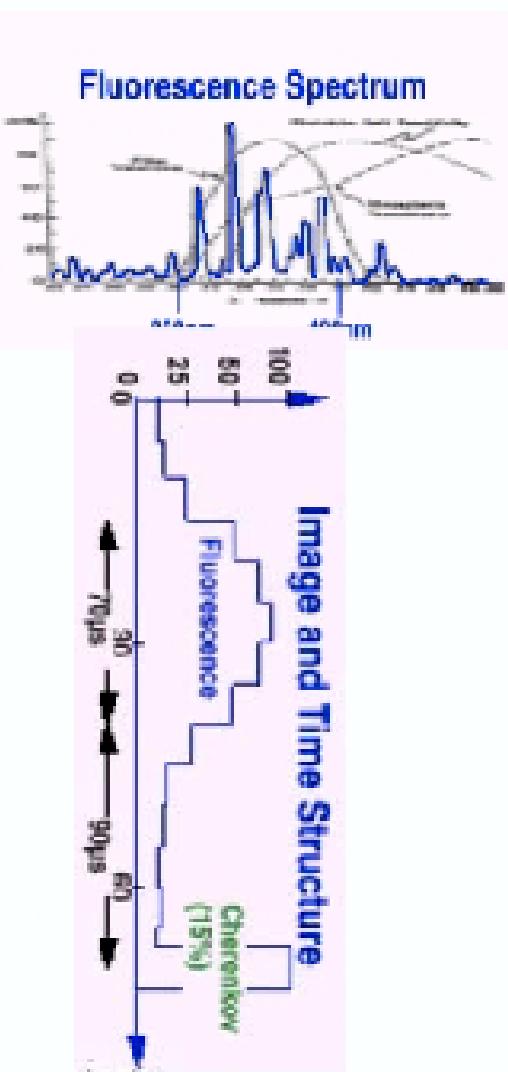
### EUSO Geometry

Detector distance = 400 km  
Total field of view = 60°  
Geometrical factor =  $5 \cdot 10^5 \text{ km}^2 \text{ sr}$   
Target air mass =  $2 \cdot 10^{12} \text{ tons}$   
Pixel size =  $(.8 \cdot .8) \text{ km}^2$





# EUSO Approach



## EUSO needs:

- 300000 Photodetectors, working in a single photon counting mode ("TPC Calorimeter")
- Sensitivity in 300-400 nm range, PD eff 30-40%
- Fast(<10 ns), compact, low weight,  
low power consuming
- Size 4x4(5x5) mm

Baseline option is MAPMT's  
(weight?power consumption?packing eff?QE?) ➤ SiPM's ?

# SiPM's for EUSO: limitations for today

1. Photon detection efficiency for 300-400 nm is too low(a few %)
2. Size 1x1 mm is only carefully studied
3. Single ph.e. dark rate should be less than dark sky rate( $\sim 1$  MHz/5x5 mm)

# SiPM: Example for superfast timing

TOF Positron Emission Tomography( TOF PET)  
with 3D reconstruction of each event

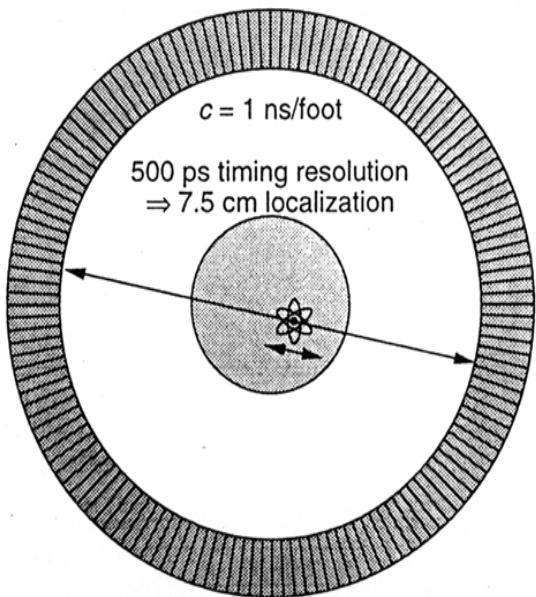


Figure 1. Time-of-Flight PET Camera. Annihilation photons are detected by a ring of scintillation crystals. With a conventional PET camera, this localizes the position of the positron to the line segment joining the two crystals. With a TOF PET camera, the arrival time difference is used to further restrict the position.

GEANT based simulation gives

FOR  
ZnO(In) crystal size      ( $4.5\text{ mm}^3$ )  
SiPM size       $4.5 \times 4.5\text{ mm}$   
Sigma of SiPM      50 ps  
Sigma electronics      5 ps  
Photon Detection eff. 30%

3D TOF PET resolution  
of 2 mm(sigma) can be achieved  
(TOF timing of 13 ps for  $\sim 400\text{ph.e}$ )  
<sub>1,2</sub>

SiPM: Limitations: \* Size  $4.5 \times 4.5\text{mm}$ , \* PD efficiency 30%

# Interesse duale dei SiPM

- *Imaging 3d, terza coordinata spaziale ottenuta con la temporizzazione*

- *applicazioni automobilistiche (con illuminazione attiva)*

$$10 \text{ ps} = 3 \text{ mm} / 2 = 1.5 \text{ mm}$$

- *applicazioni mediche (senza illuminazione attiva)*  $10 \text{ ps} = 3 \text{ mm}$

# Convenzione Quadro PAT-INFN

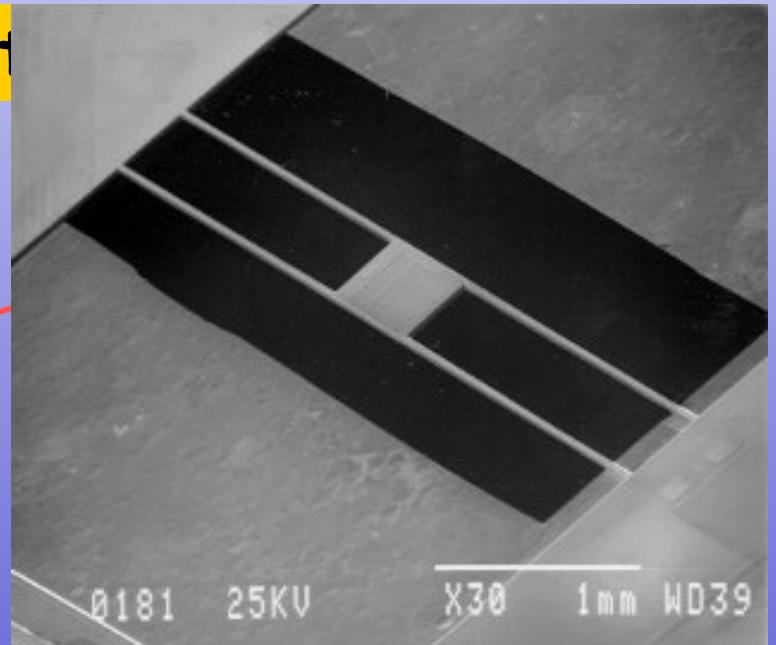
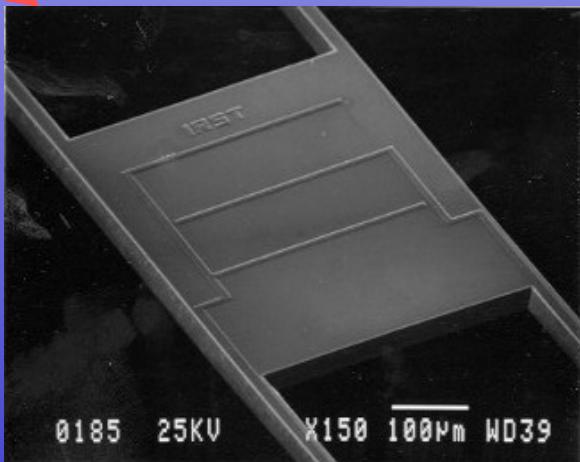
**Programma MEMS**

**P3. Sviluppo di matrici di  
Microbolometri**

# Bolometri criogenici

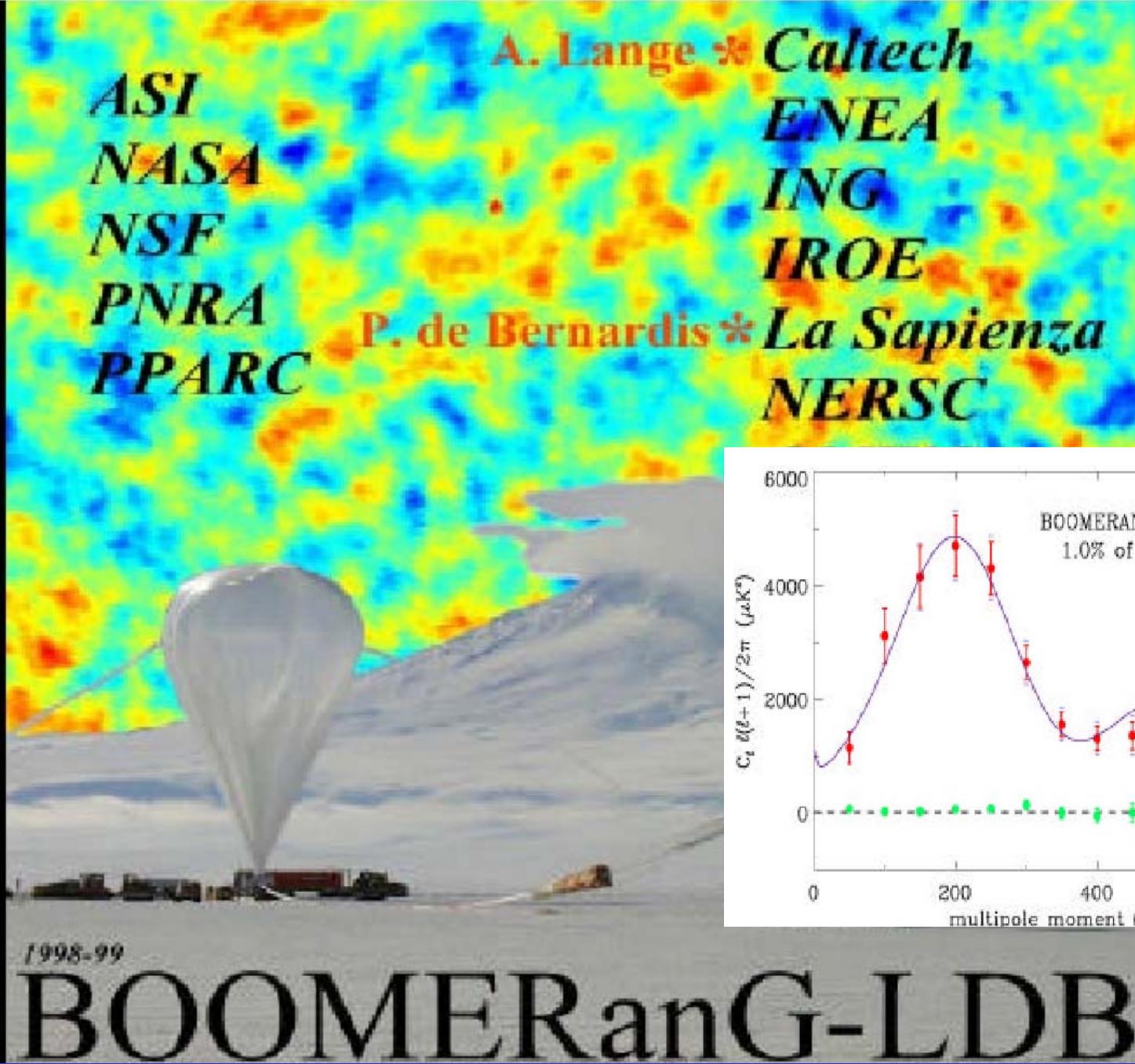
Tecnologia per microbolometri

Con il micromachining è possibile integrare il link termico

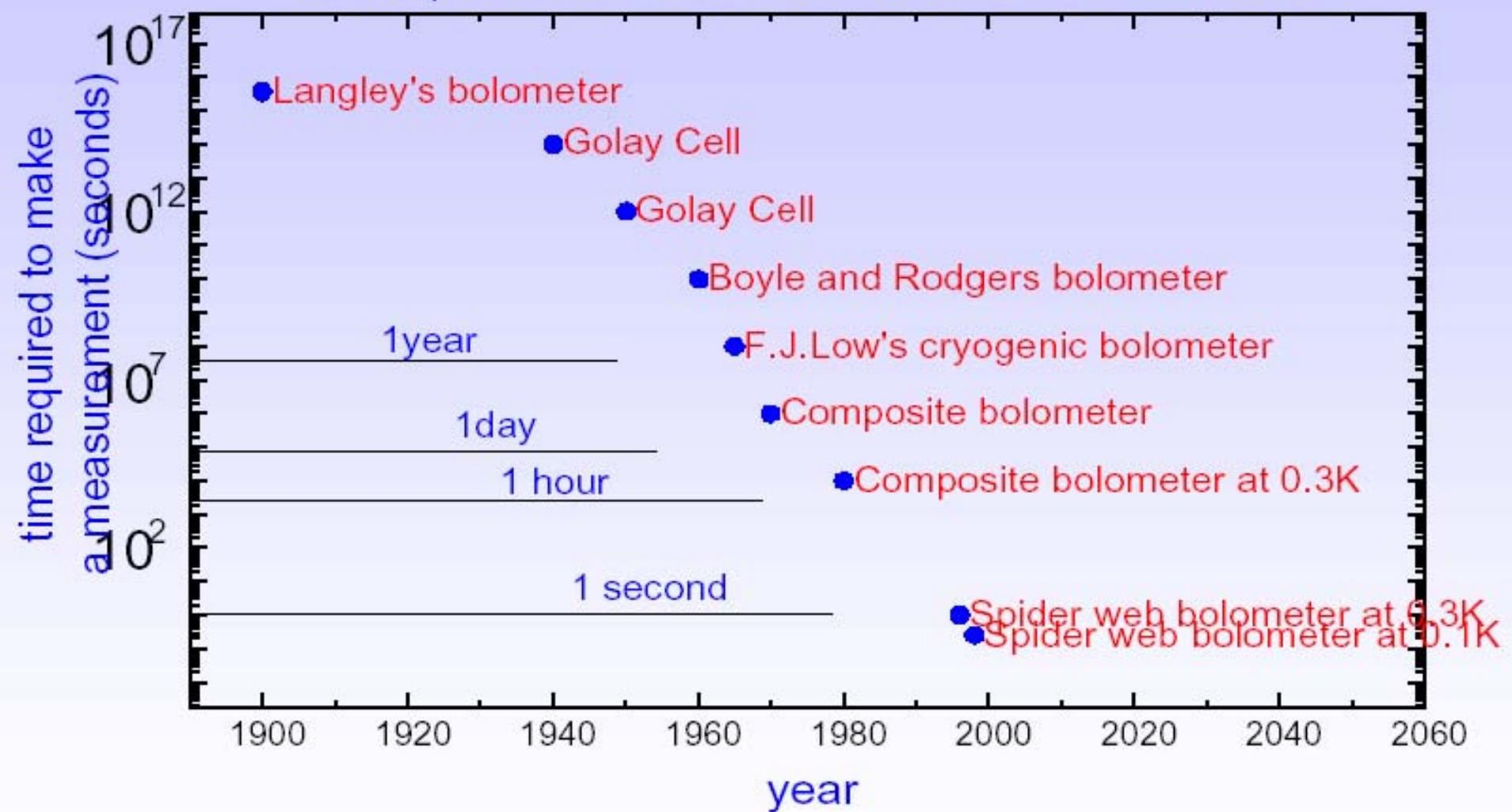


Microcalorimetro integrato realizzato con impianto multiplo in silicio e lavorazione micromeccanica

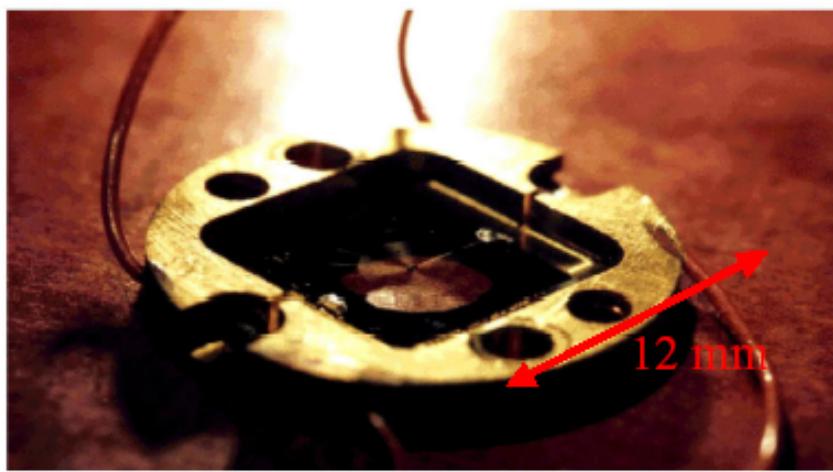
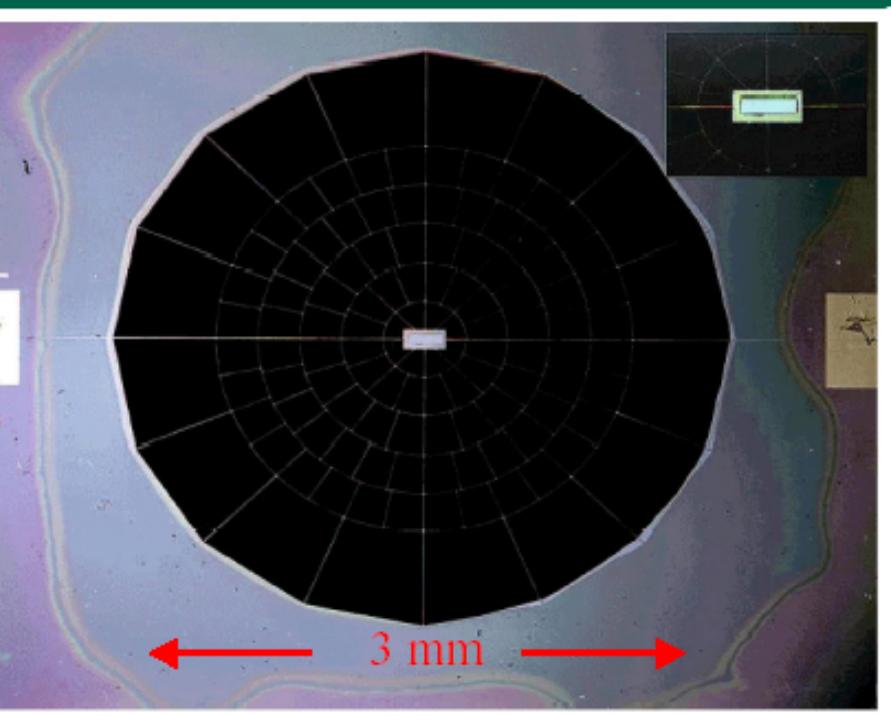
<http://oberon.roma1.infn.it/boomerang>  
<http://www.physics.ucsb.edu/~boom>



## Development of thermal detectors for far IR and mm-waves



# 1) the detectors (Caltech/JPL)



Cosmic Rays events are 10 times more frequent than at temperate latitudes

Spider web bolometers have been custom developed at JPL-Caltech for this application. The absorber is micromachined as a web of metallized  $\text{Si}_3\text{N}_4$  wires, 2  $\mu\text{m}$  thick, with 0.1 mm pitch. This is a good absorber for mm-wave photons and features a very low cross section for cosmic rays. Also, the heat capacity is reduced by a large factor with respect to the solid absorber.

NEP  $\sim 2 \cdot 10^{-17} \text{ W/Hz}^{0.5}$  is achieved @0.3K

In the focus of our telescope the sensitivity is enough to detect the heat of a coffee-maker on the moon in 1 second. ( $150\mu\text{K}_{\text{CMB}}$  in 1 s)

They have been selected for the ESA mission Planck.

Mauskopf *et al.* Appl.Opt. **36**, 765-771, (1997)

# Uncooled InfraRed Sensors

## InfraRed Imaging System

Option A: a single device in CMOS compatible technology

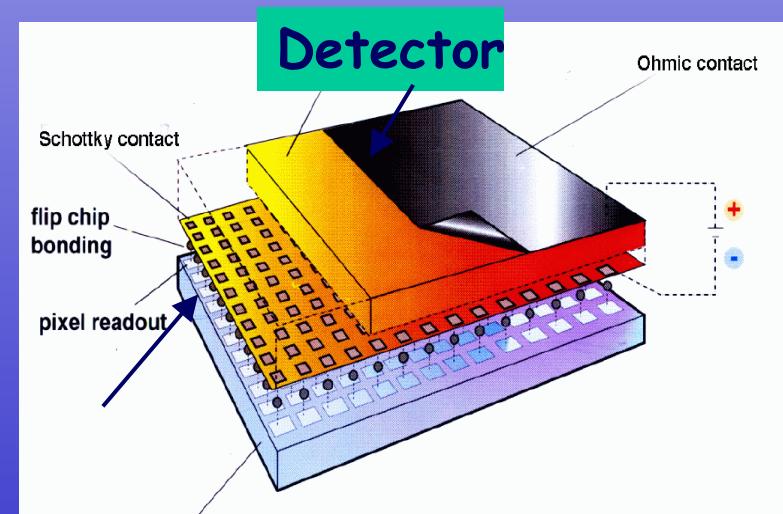
- o Integration of bolometer and readout circuits at pixel level

Option B: bolometer array in dedicated technology readout circuits in standard CMOS technology

- o 2D array of bolometers in IRST technology

- o 2D array of readout circuits in standard CMOS technology

- o Bump bonding and flip chip assembly technologies



Electronic chip

# Interesse duale delle matrici di bolometri

*-Imaging IR a temperatura ambiente*

# Convenzione Quadro PAT-INFN

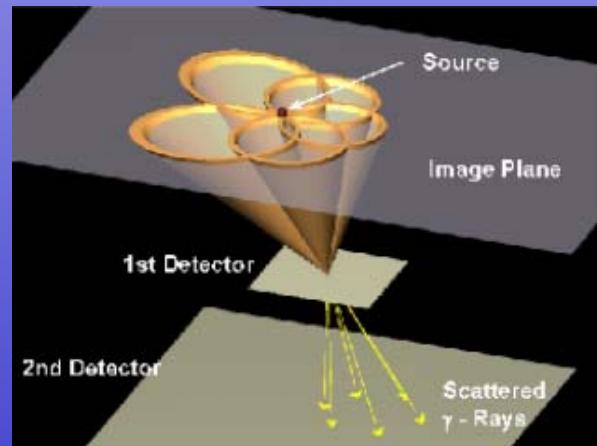
**Programma MEMS**  
**P4. Sviluppo Silicon TPC**  
**(freddo)**  
**e silicio spesso**  
**(temperatura ambiente)**

# The measured quantities in Compton imaging are:

- x, y, z-coordinates in the first detector
- x, y, z-coordinates in the second detector
- Energy of recoil electron in first detector
- Energy of scattered photon in second detector

• **Not measurable** with Compton Cameras for medical applications: Direction of recoil electron, which leads to the conical ambiguity. This leads to more complicated image reconstruction algorithms.

Illustration of conical ambiguity in the reconstruction of a point source



# Interesse duale del Silicio spesso

- *Applicazioni mediche (high resolution PET)*
- *Applicazioni astrofisiche*